

Greetings

www.sematech.org/public/resources/ediag/index.htm

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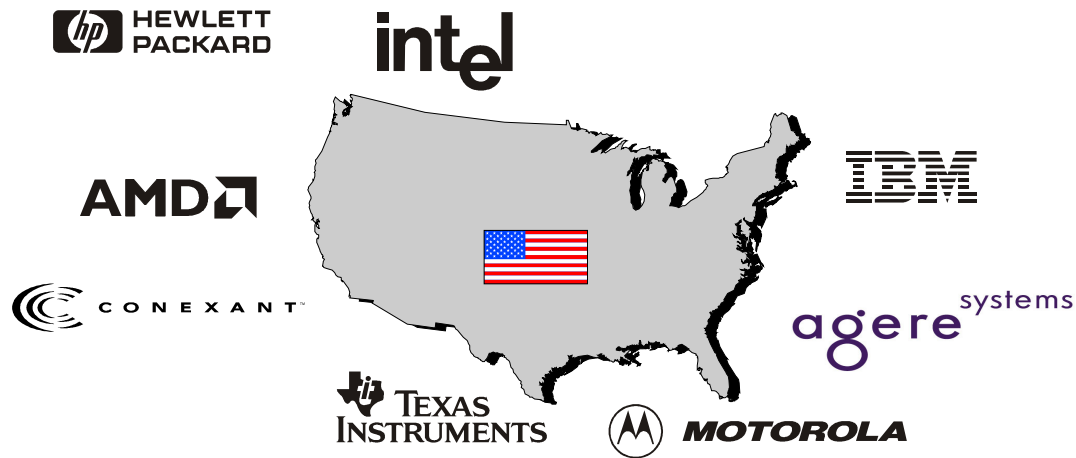
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Selete - 13 IC Makers Collaborating



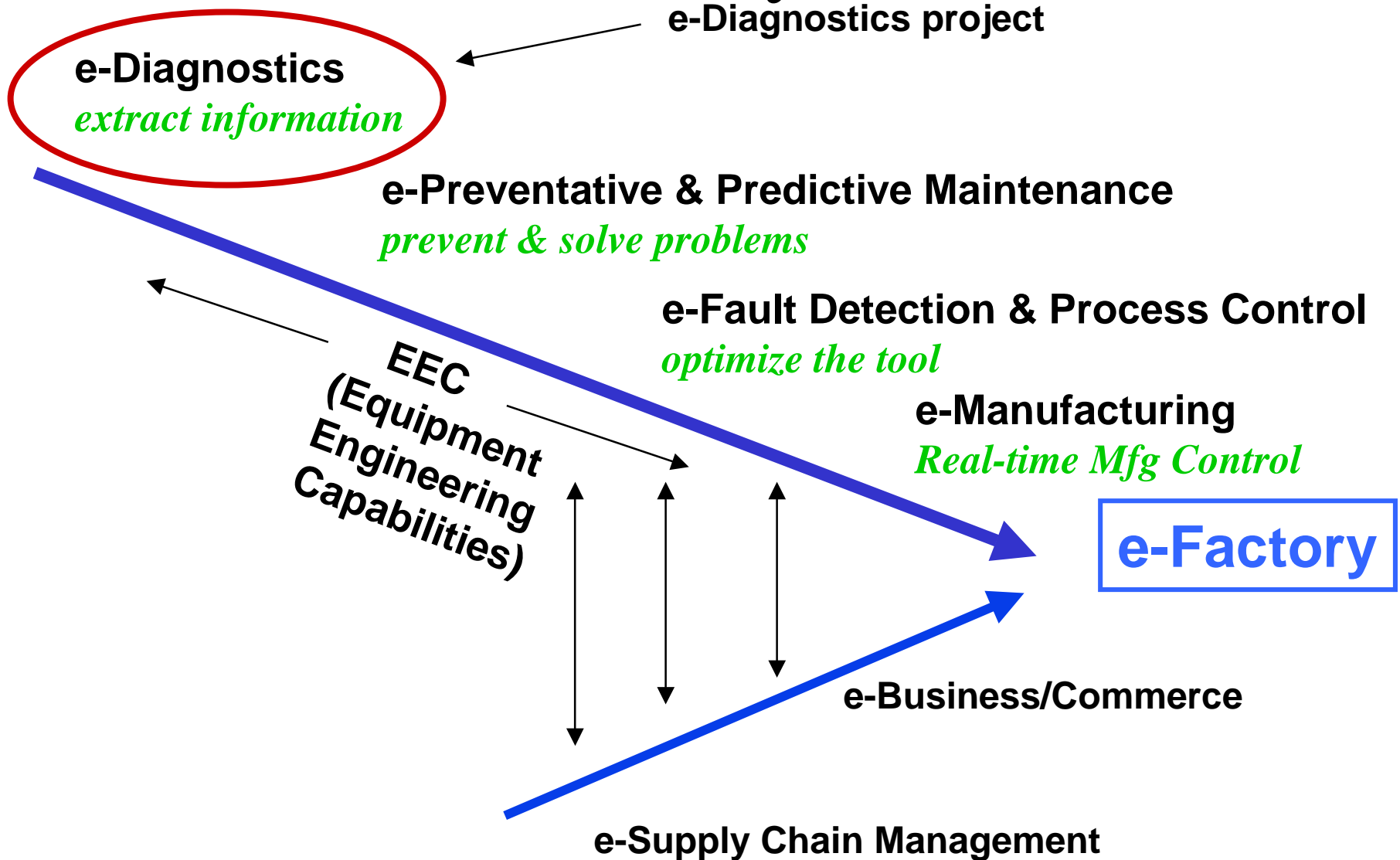
Semiconductor Leading Edge Technologies, Inc.

International SEMATECH 13 IC Makers Cooperating

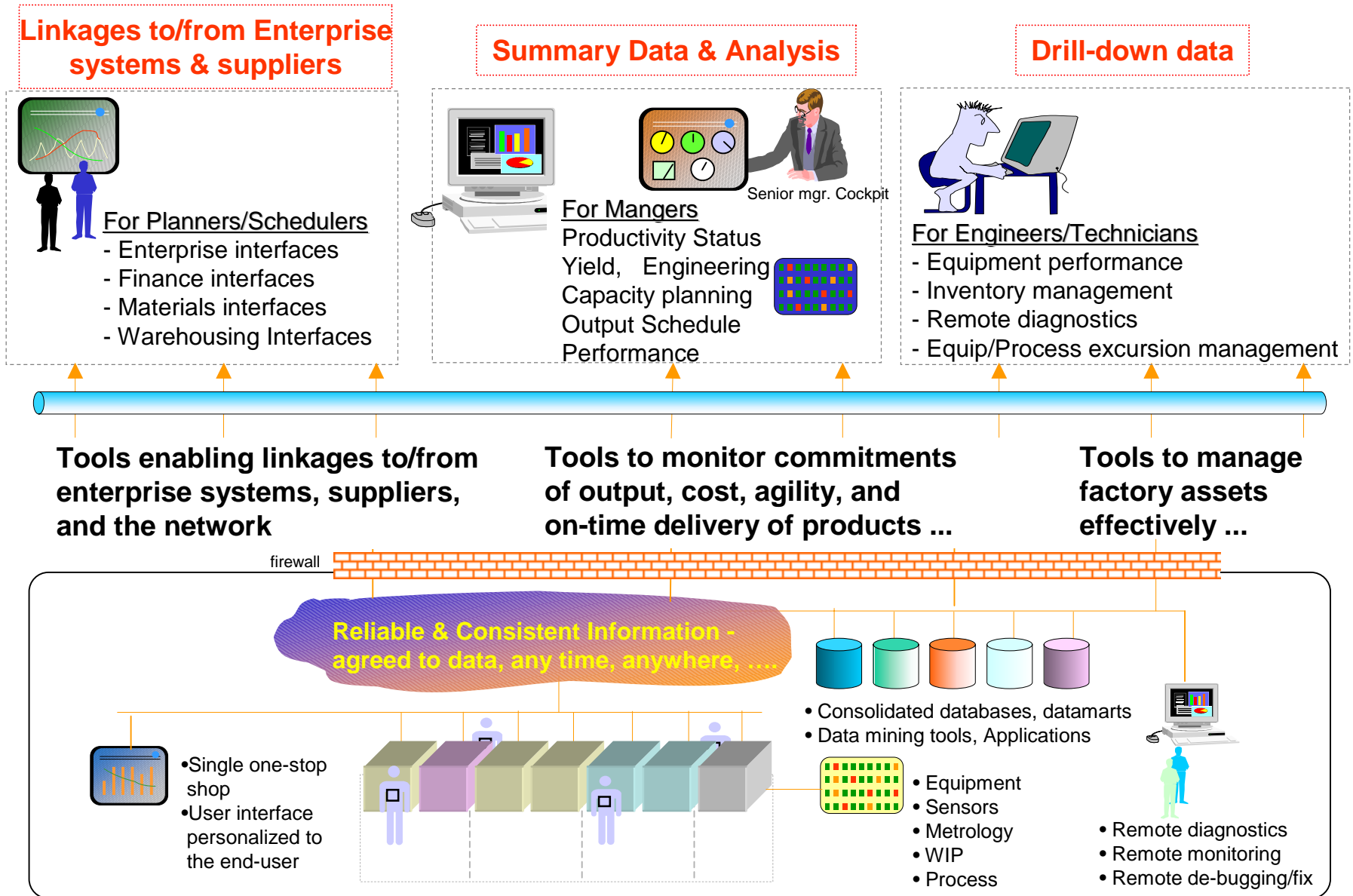


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Path to e-Factory - ISMT

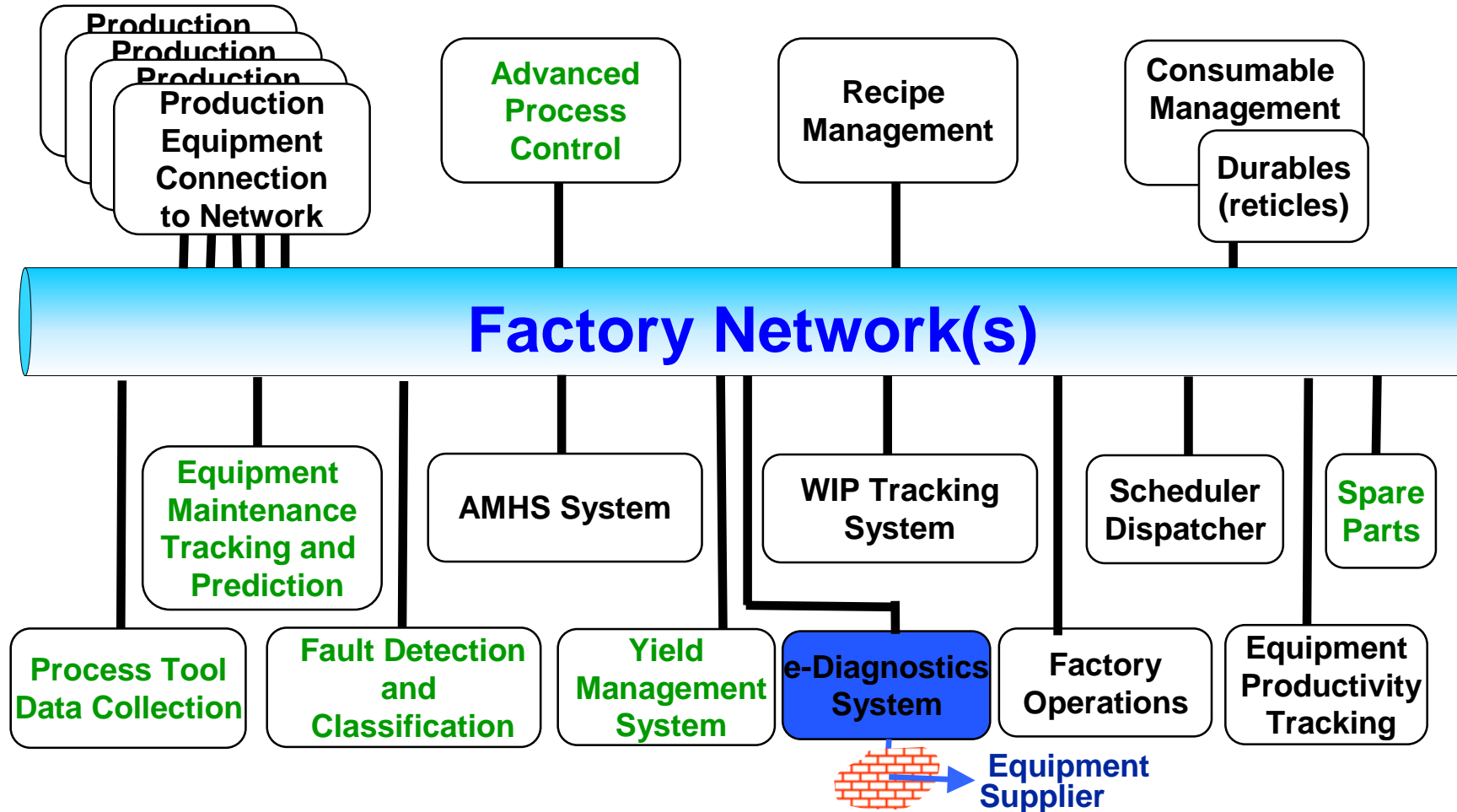


An e-Manufacturing Vision



OEE Improvement through Global Factory Information System Guidelines

These components many exist in today's factories



ISMT e-Diagnostic Capability Definitions

Level 3 - Prediction:

Predictive Maintenance, Self
Diagnostics, Automated Notification

Level 2 - Analysis:

Automated Reporting and
Advanced Analysis with SPC capability

Level 1 - Collection and Control:

Remote Tool Operation, Remote Performance
Monitoring, Remote Equipment Configuration

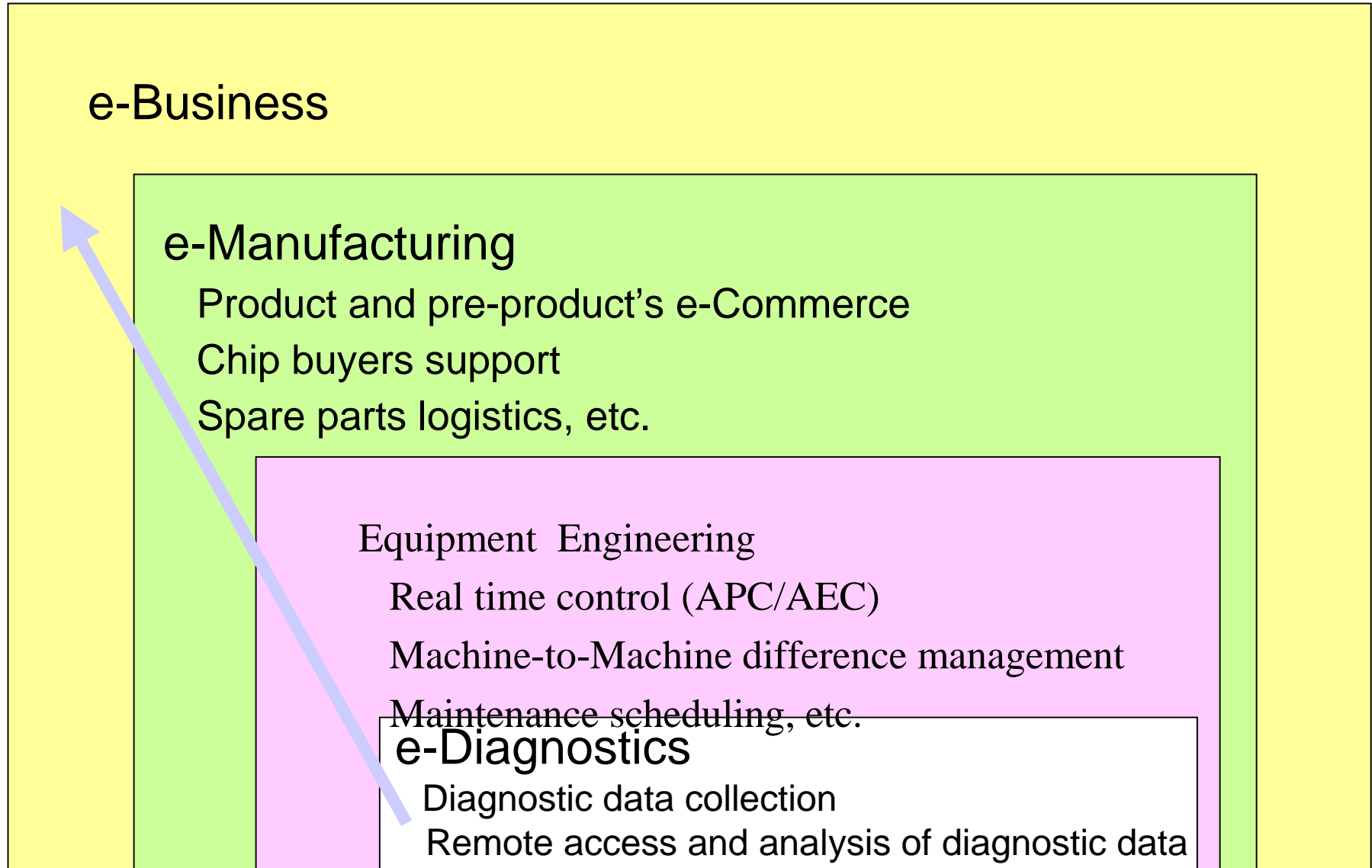
Level 0 - Access and Remote Collaboration:

Remote connectivity to the tool and remote
collaboration capabilities (text, audio, video)

Full capability definition document available at:

<http://www.semtech.org/public/resources/ediag/index.htm>

EEC Collaborations



Interfaces are Key

- The prime need for a successful EEC is standard interfaces
 - Equipment interface is number one
 - IEE/DDA/EECDTT task forces will define the interface from/to equipment to factory network
 - Simpler interfaces are easiest, DATA from the equipment
 - Interfaces to Off tool EEC applications
 - Use of 3rd party supplier apps is strongly encouraged by IC makers
 - Use existing CIM framework/APC framework where possible
 - Build off existing standards where possible
 - » Starting from scratch will take longer
 - » Don't repeat history, improve existing standards if possible
 - If new standards required, align with existing standards
 - Interfaces cannot be based on proprietary systems
 - Interfaces Outside of the factory
 - Use of standard IT technology is required, NOT semiconductor specific

Considerations

- e-Diagnostics and EEC are part of an overall factory system
 - *NOT* standalone functions
 - Must operate smoothly and effortlessly with factory system (MES) (e-Diagnostics is able to function independently of MES)
- Comes after basic function
- Data integrity is most important

Path to e-Manufacturing

- Build e-Mfg vision and roadmap consensus
 - Refine and execute e-Diagnostics and EEC roadmaps
 - Transition guidelines (requirements) to standards
 - Prototype solutions to verify guidelines
 - Confirm data integrity
 - Develop factory “e” migration strategy
- Continue e-Manufacturing global collaboration
 - Future SEMICON and APC Symposiums

Thanks for your engagement and support!!

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